

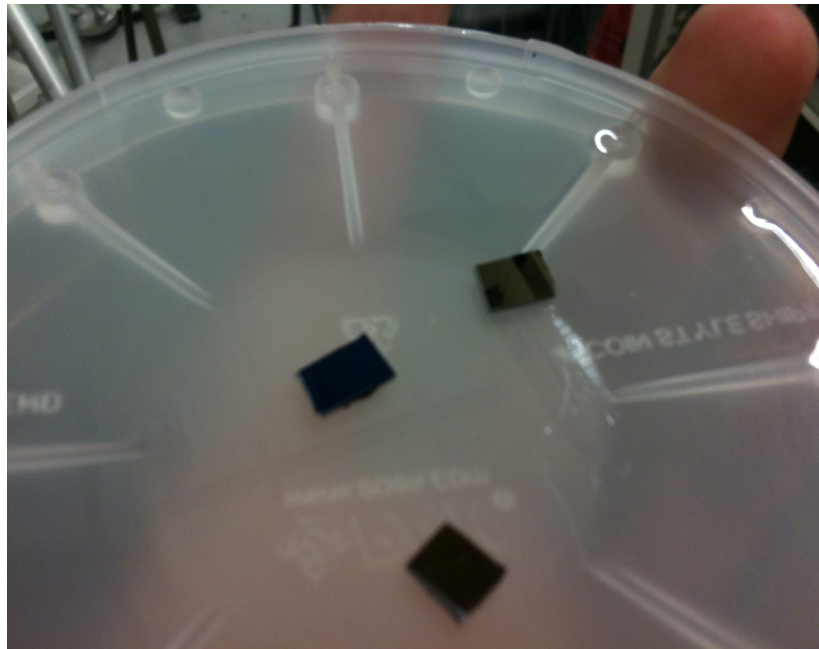
ALD Nitride - week 3

Suhas and Adair

Mentors: J Provine and Krishna
Saraswat

Progress....

variation in cycles: 400, 300, 210 (randomized errors!)



Woollam...

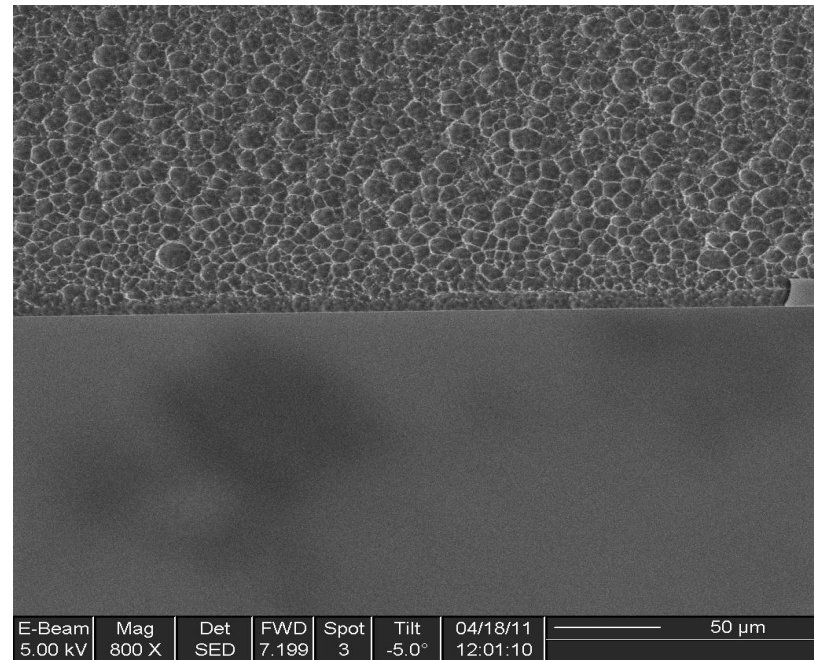
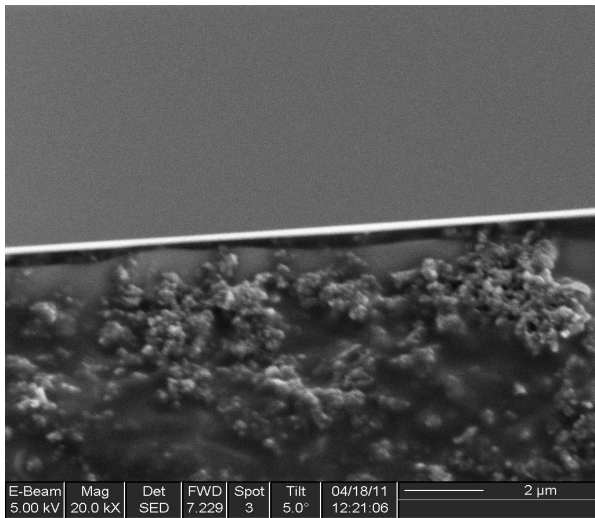
It shows a mixture of nitride and oxide....fits well to oxide for a range of longer wavelengths....

fits well to nitrides for shorter wavelengths

so...could not determine a thickness...we plan to get XPS data to feed into the woollam and get the thickness out

SEM was another option...

decoration etch was done with Xactix...XeF2...
works well for contrast...but SEM for measuring film thickness
in less than 100nm has intrinsic limitations.



coming up: XPS and woollam...SIMS?